

SEMI China CS Std. Technical Committee

Silicon Carbide substrate Task Force

Lu Min, 09.22/2021



CONNECT - COLLABORATE - INNOVATE - GROW - PROSPER

Leaders of Silicon Carbide substrate Task Force

| No. | Name | Company | Industry Chain |
|-----|------|---------|--------------------------|
| 1 | 陆敏 | 化合物半导体 | Silicon Carbide Industry |
| 2 | 郑红军 | 北京三平泰克 | Material R&D Company |
| 3 | 闫方亮 | 米格实验室 | Testing company |

Members of Silicon carbide substrate Task Force

| No. | Name | Company | Industry Chain |
|-----|--------------|-----------|------------------------------|
| 1 | 赵然 | 国宏中宇 | Substrate manufacturer |
| 2 | 林健 | 中电科46所 | Substrate R&D Institution |
| 3 | 余宗静 | 天科合达 | Substrate manufacturer |
| 4 | 钮应喜 | 芜湖启迪 | Epitaxial production |
| 5 | 冯淦 | 瀚天天成 | Epitaxial production |
| 6 | 唐为华 | 北京邮电大学 | Substrate R&D Institution |
| 7 | 孙聂枫 | 中电科13所 | Substrate R&D Institution |
| 8 | Tom Barbieri | Wolfspeed | Substrate & Epi manufacturer |
| 9 | 刘国友 | 株洲中车时代电气 | Device manufacturing |
| 10 | 蓝文安 | 浙江博蓝特 | Substrate manufacturer |
| 11 | 杨世兴 | 山东天岳 | Substrate manufacturer |
| 12 | 赵丽丽 | 科友半导体 | Substrate manufacturer |
| 13 | 侯晓蕊 | 山西烁科 | Substrate manufacturer |
| 14 | 李玲 | 国家电网 | Device manufacturing |
| 15 | 唐军 | 中电化合物 | Substrate & Epi manufacturer |

3 standards under development (在研3项标准)

| No. | Project number | Doc. Name | Proposed Company |
|-----|----------------|--|------------------|
| 1 | 6767 | Test Method for Flatness of Silicon Carbide Wafers by Optical Interference 碳化硅平整度的光学干涉测量方法 | Mige Lab |
| 2 | 6768 | Test Method for Micropipe Density of Silicon Carbide Wafer by Laser Reflection 碳化硅微管密度的激光反射测量方法 | Mige Lab |
| 3 | 6769 | Test Method for Residual Stress of Silicon Carbide Wafers by Photoelastic 碳化硅应力的光弹效应测量方法 | Mige Lab |

After internal discussions in the Task Force, the first draft has been completed.

Prepare for global voting.

经过工作组内部研讨，已完成初稿。准备全球投票。

THANK YOU



**Silicon Carbide Makes
Life Better**